

In the Specification

Please amend the specification of this application as follows:

Rewrite the paragraph at page 1, lines 4 to 10 as follows:

--This application is a divisional of copending U.S. Serial No. 09/798,561 ~~{Docket No. TI-30495}~~ filed on March 2, 2001 and incorporated herein by reference. U.S. Serial No. 09/798,561 claims the priority under 35 U.S.C. 119(e)(1) of the following copending U.S. provisional applications: 60/186,326 ~~{Docket TI-30526}~~ filed on March 2, 2000; and 60/219,340 ~~{Docket TI-30498}~~ originally filed on March 2, 2000 as non-provisional U.S. Serial No. 09/515,093 and thereafter converted to provisional application status by a petition granted on August 18, 2000.--

Rewrite the paragraph at page 2, lines ~~4~~⁴ to 9 as follows:

--Functional testing, wherein a designer is responsible for generating test vectors that are intended to ensure conformance to specification, still remains a widely used test methodology. For very large systems this method proves inadequate in providing a high level of detectable fault coverage. Automatically generated test ~~patterns~~ patterns would be desirable for full testability, and controllability and observability are key goals that span the full hierarchy of test (from the system level to the transistor level).--

Rewrite the paragraph at page 2, lines 10 to 17 as follows:

--Another problem in large designs is the long time and substantial expense involved. It would be desirable to have testability circuitry, system and methods that are consistent with a concept of design-for-reusability. In this way, subsequent devices and systems can have a low marginal design cost for testability, simulation and emulation by reusing the testability,

Amendment to the Specification
corrected by Examiner 2/3/2006
RG